Special Issue

Non-destructive Sensors and Machine Learning for Food Safety & Quality Inspection

Message from the Guest Editor

Food is routinely screened to assess quality (such as physical appearance and organoleptic properties) and safety (absence of health threatening pathogens and chemical compounds). Non-invasive sensing methods can now accommodate non-destructive, comprehensive, high-resolution spectral and image analyses for real-world safety and quality inspection on rapid food-processing lines. Topics of this special issue will include, but are not limited to:

- Spectroscopic techniques (UV-VIS, NIR, Raman, NMR, fluorescence, etc)
- Electronic nose and tongue
- Imaging methods (digital, hyperspectral, etc.)
- Fusion of multiple sensors applied to Food Analysis
- Machine learning techniques for Food Quality Inspection
- Deep learning for Automated Food Inspection
- Detection of food adulteration using Deep and Ensemble Learning
- Feature selection and extraction methods to improve classiffication tasks
- Food authentication, adulteration
- Food Quality evalution (incl. spoilage, freshness)

Guest Editor

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Message from the Editor-in-Chief

Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

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